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Print Format	3 Development of 16 dots/mm Thermal Printing Head					

Shibata, S.; Ito, M.; Nihei, K.;

Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [s also IEEE Trans. on Components, Packaging, and Manufacturing Technology, 1 A, B, C], Volume: 7, Issue: 3, Sep 1984

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4 Zirconium Nitride Thin-Film Resistors With High Thermal Durability Nozawa, T.; Suzuki, T.; Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [5 IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

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